

REMARKS

Claim 1 is presented for consideration.

The specification has been amended to include the continuing data of the subject application and to improve its idiomatic English form, and a new abstract is being submitted.

Claims 2-44 have been cancelled.

Applicants intend to file new claims in a Supplemental Preliminary Amendment in due course. If the Supplemental Preliminary Amendment is not filed before the application is taken up for examination, the Examiner is respectfully requested to contact Applicants' undersigned representative.

INFORMATION DISCLOSURE STATEMENT

In compliance with the duty of disclosure under 37 C.F.R. §1.56 and in accordance with the practice under 37 C.F.R. §§1.97 and 1.98, the Examiner's attention is directed to the documents listed on the enclosed Form PTO-1449.

In accordance with the provisions of 37 C.F.R. §1.97(d), copies of the listed documents are not enclosed because they are of record in related Application No. 09/299,878.

A partial English translation of a Japanese Office Action dated July 9, 2001, in a corresponding Japanese patent application providing a description of Japanese Application No. 9-009181 is enclosed.

A partial English translation of a Japanese Office Action dated July 2, 2001, in a corresponding Japanese patent application is enclosed.

A partial English translation of a Korean Office Action dated May 25, 2001, in a corresponding Korean patent application is enclosed. For the Examiner's additional information, Korean Patent No. 10-0220216 corresponds to European Application No. 690,472.

A copy of a European Search Report dated January 18, 2001, is enclosed. For the Examiner's additional information, U.S. Patent No. 5,834,900 corresponds to French Document No. 2,747,505.

Also enclosed is a copy of a European Search Report dated July 5, 2000, in a corresponding European patent application, and a copy of a Japanese Office Action dated February 14, 2000, in a corresponding Japanese patent application.

It is respectfully requested that the above information be considered by the Examiner and that a copy of the enclosed Form PTO-1449 be returned indicating that such information has been considered.

Applicants' undersigned attorney may be reached in our Washington, D.C. office by telephone at (202) 530-1010. All correspondence should continue to be directed to our below-listed address.

Respectfully submitted,



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FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO. 00862.002815.1		APPLICATION NO. To be assigned		
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)			APPLICANTS MITSUTOSHI KUNO, ET AL.				
Submitted to the PTO: September 16, 2003			FILING DATE September 16, 2003		GROUP 2674		
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		4,816,819	03/1989	Enari, et al.	340	811	
		4,904,895	02/1990	Tsukamoto, et al.	313	336	
		5,066,833	11/1991	Zalenski	178	19	
		3,946,381	03/1976	Johnson, et al.	340	173 R	
		5,136,397	08/1992	Miyashita	358	236	
		5,428,370	06/1995	Knapp, et al.	345	205	
		5,834,900	11/1998	Tanaka, et al.	315	169.1	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
		3-55738	03/1991	Japan			Abstract
		2-257551	10/1990	Japan			Abstract
		4-28137	01/1992	Japan			Abstract
		64-31332	02/1989	Japan			Abstract
		3-207181	09/1991	Japan			Abstract
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
		W.P. Dyke, et al., "Field Emission", Advances in Electronics and Electron Physics, Vol. VIII, pp. 89-185 (1956).					
		C.A. Spindt, et al., "Physical Properties of Thin-Film Field Emission Cathodes with Molybdenum Cones", Journal of Applied Physics, Vol. 47, No. 12, pp. 5248-5263 (December 1976).					
		M.I. Elinson, et al., "The Emission of Hot Electrons and the Field Emission of Electrons From Tin Oxide", Radio Engineering and Electronic Physics, No. 7, pp. 1290-1296 (July 1965).					
		G. Dittmer, "Electrical Conduction and Electron Emission of Discontinuous Thin Films", Thin Solid Films, Vol. 9, pp. 317-328 (1972).					
EXAMINER			DATE CONSIDERED				

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO 1449 (<i>modified</i>) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary) Submitted to the PTO: September 16, 2003				ATTY DOCKET NO. 00862.002815.1		APPLICATION NO. To be assigned	
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U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		6,121,942	10/2000	Sanou, et al.	345	75	
		6,144,154	11/2000	Yamazaki, et al.	313	495	
		5,347,292	10/2000	Ge, et al.	345	74	
		6,278,421	06/2001	Ishida, et al.	345	63	
		6,005,540	12/1999	Shinjo, et al.	345	74.1	
		5,760,538	06/1998	Mitsutake, et al.	313	422	
		6,506,087	01/2003	Fushimi, et al.	445	24	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
		11-288248	10/1999	Japan			Abstract
		9-190160	07/1997	Japan			Abstract
		8-22022	01/1996	Japan			Abstract
		11-288249	10/1999	Japan			Abstract
		8-30220	02/1996	Japan			Abstract
		2-39678	02/1990	Japan			Abstract
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
		M. Hartwell, et al., "Strong Electron Emission From Patterned Tin-Indium Oxide Thin Films, International Electron Devices Meeting, pp. 519-521 (1975).					
		H. Araki, et al., "Electroforming and Electron Emission of Carbon Thin Films", Journal of the Vacuum Society of Japan, Vol. 26, No. 1, pp. 22-29 (January 26, 1983).					
		C.A. Mead, "Operation of Tunnel-Emission Devices", Journal of Applied Physics, Vol. 32, No. 4, pp. 646-652 (April 1961).					
		R. Meyer, "Recent Development of "Microtips" Display at LETI", Technical Digest of IVMC 91, pp. 7-9 (1991).					
EXAMINER				DATE CONSIDERED			

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FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)

Submitted to the PTO: September 16, 2003

ATTY DOCKET NO.
00862.002815.1APPLICATION NO.
To be assignedAPPLICANTS
MITSUTOSHI KUNO, ET AL.FILING DATE
September 16, 2003GROUP
2674

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	6,441,544	08/2002	Ando, et al.	313	310	
	6,512,329	01/2003	Mitsutake, et al.	313	495	

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
	0 878 788	11/1998	Europe			
	0 655 722	05/1995	Europe			
	60-93741	05/1985	Japan			Abstract
	WO 99/24961	05/1999	PCT			
	2 747 505	10/1997	France			
	9-199006	07/1997	Japan			Abstract
	10-0220216	06/1999	Korea			No
	0 690 472	01/1996	Europe			
	9-9181	01/1997	Japan			Abstract
	0 725 420	08/1996	Europe			
	0 604 930	07/1994	Europe			
	0 688 035	12/1995	Europe			
	0 661 726	07/1995	Europe			

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

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